This workshop will review the use of FT-IR, Raman, UV-VIS and XRF microspectroscopy in forensic science. These techniques will be described in detail. The ability to both see and identify minute amounts of material through a microscope is enhanced by adding spectroscopy to the microscope combining spectroscopy with optical microscopy. Participants will have the opportunity to hear experts in the field of forensic science and instrumentation describe and demonstrate how microspectroscopy is put to great effect in trace analysis. Real forensic examples will be provided to illustrate the power of microspectroscopy to provide key evidence to help solve crimes. There will also be a hands-on session in which workshop attendees will be able to run samples on FT-IR, Raman and XRF microscopes.